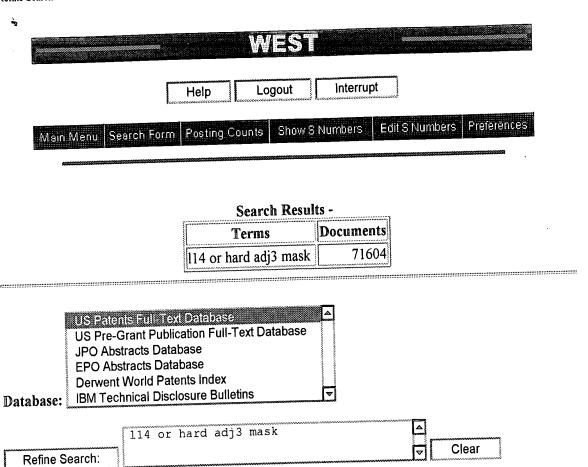


Today's Date: 8/17/2001

DB Name	Query	Hit Count	Set Name	
USPT	140 and 16	0	<u>L41</u>	
USPT	139 and 135	30	<u>L40</u>	
USPT	129 and 131	46	<u>L39</u>	
USPT	136 and 137	28	<u>L38</u>	
USPT	copper or "Cu"	260583	<u>L37</u>	
USPT	134 and 135	30	<u>L36</u>	
USPT	((438/\$)!.CCLS.)	41876	<u>L35</u>	
USPT	133 and 122	45	<u>L34</u>	~
USPT	100 and 122	47	<u>L33</u>	1.51
USPT	131 or 120	5381	<u>L32</u>	V
	oxynitride	5205	<u>L31</u>	
USPT	129 and 120	1	<u>L30</u>	
USPT	129 and 121	59	<u>L29</u>	
USPT	120 and 121			

مسرفة				T 00			
A	USPT	127 and 117	89	<u>L28</u>			
	USPT	√126 and 115	220	<u>L27</u>			
	USPT	125 and 111	807	<u>L26</u>			
	USPT	424 and 110	1120	<u>L25</u>			
	USPT	123 and 114	1460	<u>L24</u>			
	USPT	J3 and 116	5874	<u>L23</u>			
	USPT	112 near8 121	8242	<u>L22</u>			
	USPT	trench\$4	20669	<u>L21</u>	100	6 . 4	121
	USPT	118 or 119	236	<u>L20</u>)	120	CY.	121
	USPT	bottom adj antireflect\$4 adj coat\$3	31	<u>L19</u>			
	USPT	BARC	221	<u>L18</u>			
	USPT	112 near8 116	1926	<u>L17</u>			
	USPT	14 or 15	55500	<u>L16</u>			
	USPT	112 near8 114	16632	<u>L15</u>			
	USPT	18 or 19	71161	<u>L14</u>			
	USPT	112 near8 111	88671	<u>L13</u>			
	USPT	remov\$4 or etch\$4	1538586	<u>L12</u>			
	USPT	via or hole\$1	1273397	<u>L11</u>			
	USPT	pattern\$3 or photoresist	495120	<u>L10</u>			
	USPT	nitride or oxynitride	71127	<u>L9</u>			
	USPT	hardmask	230	<u>L8</u>			
	USPT	SiLK	19386	<u>L7</u>			
	USPT	14 same 15	134	<u>L6</u>			
	USPT	organic near3 polymer	37160	<u>L5</u>			
	USPT	SILK	19386	<u>L4</u>			
	USPT	semiconduct\$4	231402	<u>L3</u>			
	USPT	WEST-JEFFERSON!	34	<u>L2</u>			
	USPT	KRAFT-ROBERT!	5	<u>L1</u>			



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DB Name	Query	Hit Count	Set Name	
USPT	114 or hard adj3 mask	71604	<u>L55</u>	
USPT	152 and 153	1	<u>L54</u>	
USPT	112 near8 132	682	<u>L53</u>	
USPT	150 and 132	47	<u>L52</u>	
USPT	150 or 132	5391	<u>L51</u>	
USPT	149 and 121	57	<u>L50</u>	_
USPT	147 and 148	86	<u>L49</u>	
USPT	112 near8 15	1257	<u>L48</u>	
USPT	146 and 115	188	<u>L47</u>	
USPT	145 and 111	683	<u> L46</u>	
USPT	144 and 110	946	<u>L45</u>	
USPT	143 and 114	1245	<u>L44</u>	
USPT	142 and 114	1245	<u>L43</u>	

÷w	13 and 15	4621	<u>L42</u>
USPT	13 and 15	0 =	L4T
USPT	139 and 135	30	<u>L40</u>
USPT	129 and 131	46	<u>L39</u>
USPT	136 and 137	28	<u>L38</u>
USPT	copper or "Cu"	260583	<u>L37</u>
USPT	134 and 135	30	<u>L36</u>
USPT	((438/\$)!.CCLS.)	41876	<u>L35</u>
USPT USPT	133 and 122	45	<u>L34</u>
USPT	129 and 132	47	<u>L33</u>
USPT	131 or 120	5381	<u>L32</u>
USPT	oxynitride	5205	<u>L31</u>
	129 and 120	1	<u>L30</u>
USPT USPT	128 and 121	59	<u>L29</u>
USPT	127 and 117	89	<u>L28</u>
USPT	126 and 115	220	<u>L27</u>
	125 and 111	807	<u>L26</u>
USPT	124 and 110	1120	<u>L25</u>
USPT	123 and 114	1460	<u>L24</u>
USPT USPT	13 and 116	5874	<u>L23</u>
USPT	112 near8 121	8242	<u>L22</u>
USPT	trench\$4	20669	<u>L21</u>
USPT	118 or 119	236	<u>L20</u>
USPT	bottom adj antireflect\$4 adj coat\$3	31	<u>L19</u>
USPT	BARC	221	<u>L18</u>
USPT	112 near8 116	1926	<u>L17</u>
USPT	14 or 15	55500	<u>L16</u>
USPT	112 near8 114	16632	<u>L15</u>
USPT	18 or 19	71161	<u>L14</u>
USPT	112 near8 111	88671	<u>L13</u>
USPT	remov\$4 or etch\$4	1538586	<u>L12</u>
USPT	via or hole\$1	1273397	<u>L11</u>
USPT	pattern\$3 or photoresist	495120	<u>L10</u>
USPT	nitride or oxynitride	71127	<u>L9</u>
USPT	hardmask	230	<u>L8</u>
USPT	SiLK	19386	<u>L7</u>
USPT	14 same 15	134	<u>L6</u>
USPT	organic near3 polymer	37160	<u>L5</u>
OSPI	Organio mani- Pari		

WEST 2.0 Refine Search

•	OH V	19386	<u>L4</u>
USPT	SILK	231402	<u>L3</u>
USPT	semiconduct\$4		
TICDT	WEST-JEFFERSON!	34	<u>L2</u>
USPT	• •	5	<u>L1</u>
USPT	KRAFT-ROBERT!		



WEST

Freeform Search

Database:	US Patenis Full-Text Database US Pre-Grant Publication Full-Text Database JPO Abstracts Database EPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
	121 and 122
Term:	
Display: Generate:	Documents in Display Format: TI Starting with Number 1 O Hit List • Hit Count • Image
	Search Clear Help Logout Interrupt
	Main Menu Show S Numbers Edit S Numbers Preferences

Search History

Today's Date: 8/17/2001

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DB Name	<u>Query</u>	Hit Count	
USPT	l21 and l22	6	<u>L23</u>
USPT	19 near8 114	216	<u>L22</u>
USPT	120 and 18	12	<u>L21</u>
USPT	117 and 118	26	<u>L20</u>
USPT	117 abd 118	3668	<u>L19</u>
USPT	hard adj3 mask	1608	<u>L18</u>
USPT	116 and 114	215	<u>L17</u>
USPT	115 and 13	5525	<u>L16</u>
USPT	11 and 12	100537	<u>L15</u>
USPT	. 111 or 113	1106	<u>L14</u>
USPT	intermetal near2 dielectric near2 layer\$1	409	<u>L13</u>
USPT	intrametal near2 dielectric	3	<u>L12</u>
USPT	IMD	845	<u>L11</u>
USPT	intrametal near2 dielectric near2 layer	2	<u>L10</u>
USPT	etch\$4 or remov\$	1486429	<u>L9</u>
USPT	15 or 16 or 17	5381	<u>L8</u>
USPT	oxynitride	5205	<u>L7</u>
USPT	BARC	221	<u>L6</u>
USPT	bottom adj antireflective adj coat\$4	27	<u>L5</u>
USPT	pattern\$4 or etch\$4	539787	<u>L4</u>
USPT	trench\$3	20577	<u>L3</u>
USPT	via\$1	858202	<u>L2</u>
USPT	semiconduct\$4	231402	<u>L1</u>